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PATENTS & TRADEMARK OFFICE

Application Serial No. 10/803,264
Response to July 8, 2005 OA

MI22-2524

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/803,264
Filing Date March 17, 2004
Confirmation No. 5382
Inventor..... Warren M. Farnworth et al.
Assignee..... Micron Technology, Inc.
Group Art Unit..... 2829
Examiner Russell M. Kober
Attorney's Docket No. MI22-2524
Customer No.. 021567
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO JULY 8, 2005 OFFICE ACTION

To: Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: D. Brent Kenady
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Responsive to the July 8, 2005 Office Action, Applicant amends and remarks as follows:

AMENDMENTS

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.

EV633262181